## 11th European Symposium on Semiconductor Detectors



Contribution ID: 21 Type: not specified

## Plasma effects in silicon detectors for the European XFEL and their impact on sensor performance

Wednesday, 10 June 2009 18:00 (20 minutes)

**Presenter:** BECKER, Julian (University of Hamburg)

**Session Classification:** Defects in Semiconductors and Radiation Tolerance